

| Parameter | Symbol | Conditions | Values | | Unit | |
|---------------------------------------|---------------------|--|--------|------|------|-----|
| | | | min. | typ. | max. | |
| Thermal characteristics ²⁾ | | | | | | |
| Thermal resistance, junction - case | $R_{ m thJC}$ | - | - | - | 1.1 | K/W |
| SMD version, device on PCB | R_{thJA} | minimal footprint | - | - | 62 | |
| | | 6 cm ² cooling area ³⁾ | - | - | 40 | |

Electrical characteristics, at $T_{\rm j}$ =25 °C, unless otherwise specified

Static characteristics

| Drain-source breakdown voltage | $V_{(BR)DSS}$ V_{GS} =0V, I_D = -1mA | | -30 | - | - | V |
|----------------------------------|--|--|------|-------|------|----|
| Gate threshold voltage | $V_{\rm GS(th)}$ | $V_{\rm DS} = V_{\rm GS}, I_{\rm D} = -253 \mu A$ | -1.0 | -1.5 | -2.0 | |
| Zero gate voltage drain current | I _{DSS} | $V_{\rm DS}$ =-24V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =25°C | - | -0.05 | -1 | μA |
| | | $V_{\rm DS}$ =-24V, $V_{\rm GS}$ =0V, $T_{\rm j}$ =125°C ²⁾ | - | -20 | -200 | |
| Gate-source leakage current | I _{GSS} | V _{GS} =-16V, V _{DS} =0V | - | - | -100 | nA |
| Drain-source on-state resistance | R _{DS(on)} | V _{GS} =-4.5V, I _D =-90A | - | 5.1 | 6.8 | mΩ |
| | | V _{GS} =-10V, I _D =-90A | - | 3.3 | 4.1 | |



| Parameter | Symbol | Conditions | Values | | | Unit |
|---|----------------------|--|--------|------|-------|------|
| | | | min. | typ. | max. | |
| Dynamic characteristics ²⁾ | | | | | | |
| Input capacitance | C iss | V _{GS} =0V, V _{DS} =-25V, f=1MHz | - | 8670 | 11300 | pF |
| Output capacitance | C oss | | - | 2350 | 3050 | |
| Reverse transfer capacitance | C _{rss} | | - | 65 | 130 | |
| Turn-on delay time | t _{d(on)} | $V_{\rm DD}$ =-15V, $V_{\rm GS}$ =-10V, $I_{\rm D}$ =-90A, $R_{\rm G}$ =3.5 Ω | - | 17 | - | ns |
| Rise time | t _r | | - | 11 | - | |
| Turn-off delay time | t _{d(off)} | | - | 140 | - | |
| Fall time | t _f |] | - | 40 | - | |
| Gate Charge Characteristics ²⁾ | | | ī | ı | Т | |
| Gate to source charge | Q _{gs} | | - | 29 | 38 | nC |
| Gate to drain charge | Q_{gd} | V _{DD} =-24V, I _D =-90A, | - | 15 | 30 | |
| Gate charge total | Q _g | V _{GS} =0 to -10V | - | 125 | 160 | |
| Gate plateau voltage | V _{plateau} | | - | -3.3 | - | V |
| Reverse Diode | | | | | | |
| Diode continous forward current ²⁾ | Is | T 05°0 | - | - | -90 | Α |
| Diode pulse current ²⁾ | I _{S,pulse} | - T _C =25°C | - | - | -360 |] |
| Diode forward voltage | V _{SD} | V _{GS} =0V, I _F =-90A, T _j =25°C | - | - | -1.3 | V |
| Reverse recovery time ²⁾ | t _{rr} | V _R =-15V, I _F =-50A, | - | 50 | - | ns |
| Reverse recovery charge ²⁾ | Q _{rr} | d <i>i</i> _F /d <i>t</i> =-100A/µs | - | 70 | - | nC |

¹⁾ Current is limited by bondwire; with an $R_{\rm thJC}$ = 1.1K/W the chip is able to carry -150A at 25°C.

²⁾ Defined by design. Not subject to production test.

³⁾ Device on 40 mm x 40 mm x 1.5 mm epoxy PCB FR4 with 6 cm² (one layer, 70 μm thick) copper area for drain connection. PCB is vertical in still air.



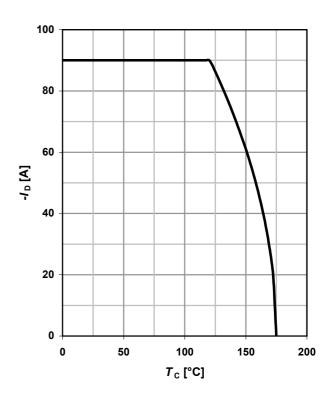
1 Power dissipation

$$P_{\text{tot}} = f(T_{\text{C}}); V_{\text{GS}} \leq -6V$$

160 140 120 100 P_{tot} [W] 80 60 40 20 0 0 50 100 200 150 *T*_c [°C]

2 Drain current

$$I_D = f(T_C); V_{GS} \le -6V$$



3 Safe operating area

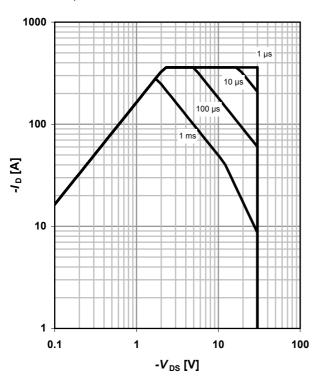
$$I_D = f(V_{DS}); T_C = 25 \,^{\circ}C; D = 0$$

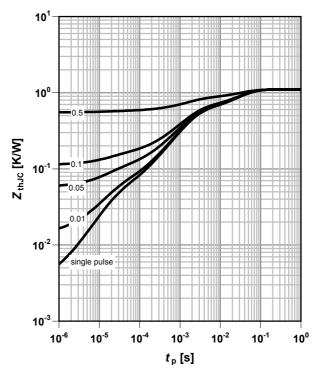
parameter: t_p

4 Max. transient thermal impedance

$$Z_{\rm thJC} = f(t_{\rm p})$$

parameter: $D = t_p/T$



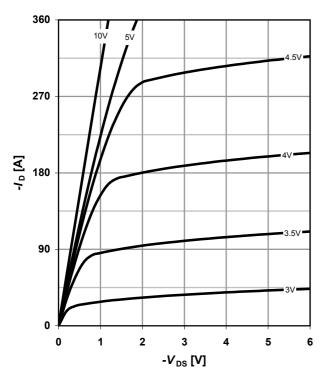




5 Typ. output characteristics

 $I_{\rm D} = f(V_{\rm DS}); T_{\rm j} = 25 \,{}^{\circ}{\rm C}$

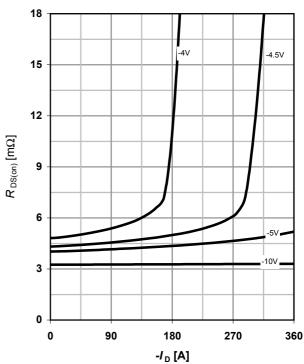
parameter: $V_{\rm GS}$



6 Typ. drain-source on-state resistance

 $R_{DS(on)} = (I_D); T_j = 25 \text{ }^{\circ}\text{C}$

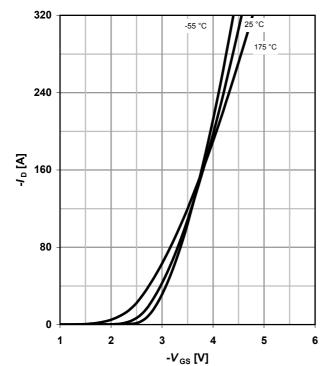
parameter: V_{GS}



7 Typ. transfer characteristics

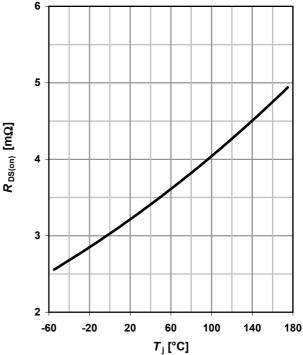
 $I_{\rm D} = f(V_{\rm GS}); V_{\rm DS} = -6V$

parameter: T_i



8 Typ. drain-source on-state resistance

$$R_{DS(on)} = f(T_j); I_D = -90 \text{ A}; V_{GS} = -10 \text{ V}$$





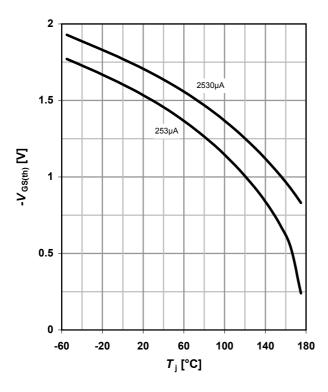
9 Typ. gate threshold voltage

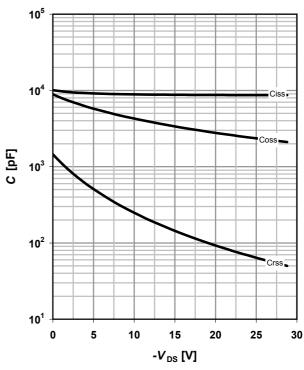
 $V_{GS(th)} = f(T_j); V_{GS} = V_{DS}$

parameter: -I_D

10 Typ. capacitances

 $C = f(V_{DS}); V_{GS} = 0 V; f = 1 MHz$





11 Typical forward diode characteristicis

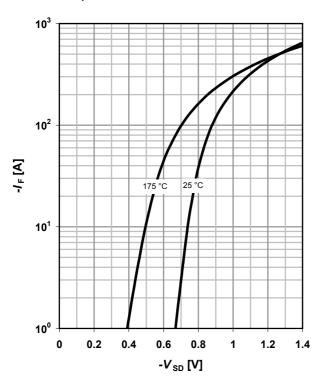
 $IF = f(V_{SD})$

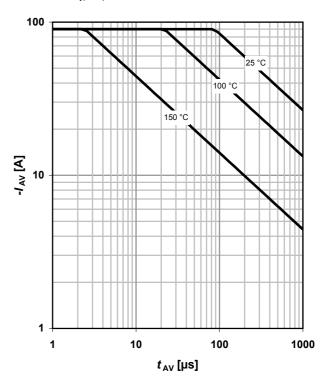
parameter: T_i

12 Avalanche characteristics

 $I_{AS} = f(t_{AV})$

parameter: T_{j(start)}







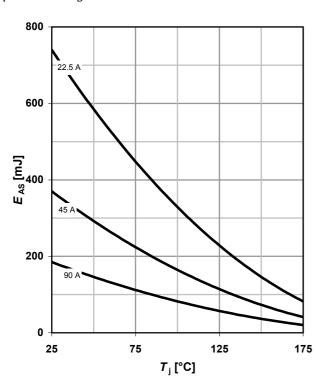
13 Avalanche energy

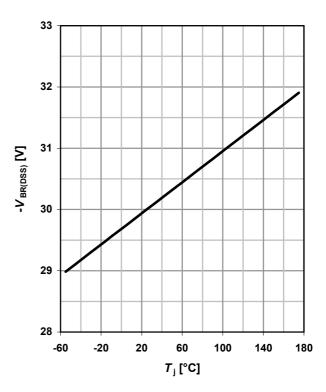
 $E_{AS} = f(T_j)$

parameter: I_D

14 Drain-source breakdown voltage

$$V_{BR(DSS)} = f(T_j); I_D = -1 \text{ mA}$$



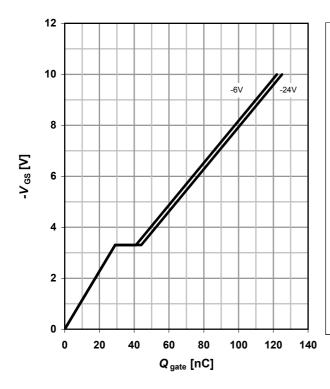


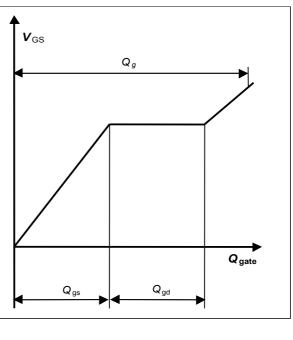
15 Typ. gate charge

 $V_{\rm GS}$ = f(Q $_{\rm gate}$); $I_{\rm D}$ = -90 A pulsed

parameter: $V_{\rm DD}$

16 Gate charge waveforms







Published by Infineon Technologies AG 81726 Munich, Germany

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Revision History

| Version | Date | Changes | |
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